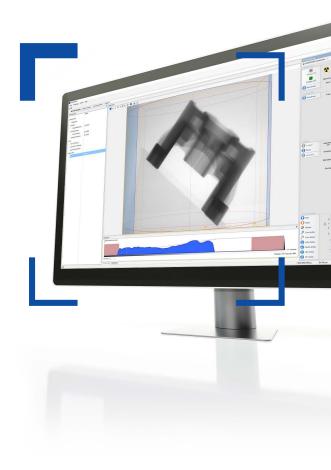
The easy way to capture meaningful volume data.



ZEISS METROTOM OS



Seeing beyond

ZEISS METROTOM OS 3.8

Your benefits in the new version



SEARCHING & FINDING IN A FASTER WAY

With the possibility of filtering according to various measurement parameters, you can now quickly and easily find, recycle or even delete measurements already made.

SCAN FASTER

The ShortScan function allows you to capture images even faster. Thus, for example, cycle times can be kept in production.

HIGHER IMAGE QUALITY

An improved artefact correction when scanning wide parts with VHD guarantees a better image quality.

ZEISS METROTOM OS

Optional software packages*

SEPARATION

With the automatic separation you increase the productivity of your ZEISS METROTOM. Thanks to this feature you can now scan several components at once and evaluate them separately. In this way you generate the volume data of each individual component. This significantly reduces the scanning time and operator interaction effort per part and minimizes the amount of data.

ADVANCED MULTI-MATERIAL ARTEFACT REDUCTION (AMMAR)

Scanning workpieces, which consist of two or more materials, results in artifacts in the volume data caused by different material thicknesses. Thanks to the AMMAR correction process, these artifacts are significantly reduced after scanning. This allows you to see more details in your parts at the transition from metal to plastic and makes the analysis of measurement results much easier.

VIRTUAL HORIZONTAL DETECTOR EXTENSION (VHD)

With the VHD option, you can measure workpieces that are wider than the detector. This increases the possible volume diameter of your captures by up to 80%. The option also allows you to achieve a higher resolution by using smaller voxel sizes, as your component can be placed closer to the X-ray tube.

^{*}Prerequisite is the ZEISS METROTOM OS 3.8 basic version.

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ZEISS METROTOM OS

Software solution for efficient CT scans

ZEISS METROTOM OS basic is the software for controlling your ZEISS METROTOM system and generating a reconstructed 3D volume.

The software is easy to operate and already includes many features in its basic version. Thus, VAST measurement, correction modules such as e.g. the scattered radiation and beam hardening corrections, the merging of several individual scans, or even the CT autofocus are included in the basic version. You are, therefore, optimally prepared for all of your measuring tasks.

Find out more about the benefits and updates of the latest version of the ZEISS system software.

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